

L Number	Hits	Search Text	DB	Time stamp
2	312	714/37.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 08:59
3	298	714/39.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 08:59
1	255	714/57.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 08:59
4	321	714/45.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 08:59
5	376	714/46.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 08:59
6	601	714/48.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 08:59
7	134	((714/37.cccls. and @ad<=20011023) (714/39.cccls. and @ad<=20011023) (714/45.cccls. and @ad<=20011023) (714/46.cccls. and @ad<=20011023) (714/48.cccls. and @ad<=20011023)) and tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 09:00
8	776	714/736.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 09:02
9	129	714/745.cccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 09:02
10	260	((714/736.cccls. and @ad<=20011023) (714/745.cccls. and @ad<=20011023)) and tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/28 09:02
-	6	(UCHIYAMA-HIROTO).in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 10:00
-	50	((714/37.cccls. and @ad<=20011023) (714/39.cccls. and @ad<=20011023) (714/45.cccls. and @ad<=20011023) (714/46.cccls. and @ad<=20011023) (714/48.cccls. and @ad<=20011023) (714/704.cccls. and @ad<=20011023) (714/736.cccls. and @ad<=20011023) (714/745.cccls. and @ad<=20011023)) and (("IC" or "integrated circuit") adj tester)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 14:50

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-	333	(("IC" or "integrated circuit") adj tester) and (sample or sampling)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 08:34
-	286	((("IC" or "integrated circuit") adj tester) and (sample or sampling)) and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 08:40
-	3326	("IC" or "integrated circuit") adj tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 14:04
-	3	(("IC" or "integrated circuit") adj tester) and (μ and σ)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 14:05
-	22	(("IC" or "integrated circuit") adj tester) and ((standard adj deviation) and (average or mean))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 14:10
-	904	714/704.ccls. and @ad<=20011023	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 15:09
-	33	(714/704.ccls. and @ad<=20011023) and tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/26 15:35

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